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Title:Terahertz dielectric response of ferroelectric BaxSr 1-xTiO3 thin films

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Abstract:Terahertz time-domain spectroscopy has been used to investigate the dielectric and optical properties of ferroelectric BaxSr 1-xTiO3 thin films for nominal x-values of 0.4, 0.6, and 0.8 in the frequency range of 0.3 to 2.5 THz. The ferroelectric thin films were deposited at approximately 700 nm thickness on [001] MgO substrate by pulsed laser deposition. The measured complex dielectric and optical constants were compared with the Cole-Cole relaxation model. The results show that the Cole-Cole relaxation model fits well with the data throughout the frequency range and the dielectric relaxation behavior of ferroelectric Ba xSr1-xTiO3 thin films varies with the films compositions. Among the compositions of BaxSr1-xTiO 3 films with different Ba/Sr ratios, Ba0.6Sr 0.4TiO3 has the highest dielectric constants and the shortest dielectric relaxation time.

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